	Specifications No.	
Messrs.		
(first · revised)  Delivery	/ Specificatio	ons
Product No : Quartz Crystal Unit V	/T-200-F	
Item code :		
Product form : 32.768kHz ± 20 × 10	0 <sup>-6</sup> / 12.5pF	
The number of copies : 1 copy		
Date of Registrantion :		
⟨NOTICE⟩		
1. Advance agreement will be needed before cha	nging any contents of the spec	cification herein.
2. Provided that the information herein is subject	to change, only revised pages	shall be reissued.
<ol><li>When the product described herein includes Reetc, they may not be exported without authorized</li></ol>		
<ol> <li>The contents of this specification including all fit (copyright or know-how) of Seiko Instruments II specifications to third parties without permission</li> </ol>	nc. It is strictly prohibited to co	
<ol><li>In the case that the products described herein a influence any one of the human body, human lif medical equipment or vehicles, please let us known.</li></ol>	e and property, such as physic	
Seiko Instruments Inc.	Dept. of Issue	Dept. of Control
Quartz Crystal Division Network Components Business	Sales Section	Quality Assurance Section
1-8, Nakase, Mihamaku, Chiba shi, Chiba 261-8507, Japan		

#### 1.Scope

These specifications apply to QUARTZ CRYSTAL RESONATORS (hereinafter referred to as RESONATORS) to be manufactured by Seiko Instruments Inc. (hereinafter referred to as <u>SII</u>) to

#### 2.Designation

RESONATORS are designated "VT-200-F" (32.768kHz).

#### 3. Shape and dimensions

As per the VT-200-F drawing shown on page 5.

#### 4.Electrical characteristics

Specified on page 2 through 3.

#### 5.Shipment and packaging

5.1 (10,000) pcs are the standard lot size to which the lot number shall be allotted 5.2 The packaging shall conform to the resonator packaging standards.

#### 6.Outgoing inspection

- 6.1 When mutually agreed, the outgoing inspection shall be conducted as per the standard on page 4.
- 6.2 The outgoing inspection slip is not basically affixed to each packaging.

#### 7.Warranty

In the event that any defective RESONATORS	or defective lot is found at
incoming inspection at	and that any defect
resulting from failu resin process-control at SII a	fter incoming inspection is
found, good RESONATORS shall be supplied to	)
free of charge as a replacement.	
In the event that any trouble or problems rising	directly from RESONATORS
occurs, it will be amicably settled between both	parties, provided that
warranty shall be done within the score of replace	cement of good RESONATORS.

#### 8. Amendment or abolition of the specifications.

Amendment or abolition of the specifications sh	all be made upon mutual
consent between	and SII If any problem arises
it shall be amicably settled between both parties	S.

#### 9.Effectiveness of the specifications

These specifications are effective after receipt of returned copies with your approved sign.

[1] The maximum rating

	Item	Symbol	Rating	Note
1	Storage temperature range	Tsto	-30 ~ +70	
2	Maximum drive level	DL max	1.0 μW max.	

[2] Recommended Operating Condition

	Item	Symbol	Rating	Note
1	Operating temperature range	Tope	-10 ~ +60	
2	Drive level	DL	0.1 μW typ.	

[3] Erectrical -Characteristics Measurement temperature : 25±2

3	Erectrical -Characteristics Measurement temperature : 25±2				
	Item	Symbol	Specifications	Conditions	
1	Nominal frequency	F <sub>0</sub>	32.768 kHz		
2	Frequency tolerance	∆f/f <sub>0</sub>	± 20 × 10 <sup>-6</sup>		
3	Load capacitance	$C_L$	12.5 pF		
4	Equivalent series resistance	R <sub>1</sub>	50 kΩ max.	Measured with ATI 4192A Impedance analyzer. OSC LEVEL = 0.1V	
5	Q-value	Q	40 × 10 <sup>3</sup> min.	calculated with the following equation: Q=(2π·Fr·L <sub>1</sub> )/R <sub>1</sub>	
6	Motional capacitance	C <sub>1</sub>	2.0 fF typ.		
7	Shunt capacitance	C <sub>0</sub>	0.9 pF typ.	Measured with ATI 4192A Impedance analyzer. OSC LEVEL = 0.1V	
8	Turnover temperature	Тр	25 ± 5	Measure this coefficient at 3 points of 10 , 25 , and 40 using	
9	Temperature coefficient	k	(-3.5±0.8)×10 <sup>-8</sup> / <sup>2</sup>	C-MOS sircuit.	
10	Aging	$\Delta f/f_0$	± 5 × 10 <sup>-6</sup> / year	25±3 、 First year	
11	Insulation resistance	IR	500 MΩ min.	Measured with ATI 4329A Insulation Resistance Meter. Apply DC100V.	

(continued)

# [4] Environment-proof · Mechanical property

No	ltem -	Specifications	Conditions		
1	High temperature storage	f/f =±5 × 10 <sup>-6</sup>	After storage under 85 for 500 hrs, measure at room temperature.		
2	Low temperature storage	f/f =±5 × 10 <sup>-6</sup>	After storage under -40 for 500 hrs, measure at room temperature.	*1	
3	High temperature and high humidity storage	f/f =±5 × 10 <sup>-6</sup>	After storage under 60 ±2 , 90 to 95% RH for 500 hrs, measure at room temperature.		
4	Thermal shock resistance	f/f =±5 × 10 <sup>-6</sup>	Measured at room temperature after 20 cycles. -25 +80 for 30 minutes.	*1	
5	Mechanical shock resistance	f/f =±5 × 10 <sup>-6</sup>	Measure after free drop of the RESONATOR three times from the height of 75cm onto a wooden board.		
6	Vibration resistance	f/f =±5 × 10 <sup>-6</sup>	Amplitude 1.5mm and 10 ~ 60Hz with cycle time 2 ~ 3 minutes in 3 direction (X,Y,and Z axis)each for 2 hrs.		
7	Resistance to soldering heat	f/f <sub>0</sub> =± 5 × 10 <sup>-6</sup>	Measured at room temperature after immersing the lead wire in a soldering bath of 300 ±10 for 5 seconds up to a position where it is 2mm away from the root of the plug.		
8	Tensile strength of lead wire	$f/f_0 = \pm 5 \times 10^{-6}$	Apply a load of 500g for 30 seconds in the lead wire's axial direction.		
9	Bending strength of lead wire	$f/f_0 = \pm 5 \times 10^{-6}$	Bending cycle: 0° 45° 0° 45° 0°	2	
10	Solderability of lead wire	A minimum 95% of the area to be coated with solder	Apply resin-flux contained-solder to a soldering iron of 280 ±5 for 5 seconds.	*2	

#### Note:

- 1. The adove tests no. 1 to 9 must be conducted independently (not series tests)
- 2. \*1: Measure after 24 hours soak at room temperature .
- 3. \*2: Measure after 2 hours soak at room temperature .
- 4. R1 is  $60k\Omega$  max. after the each above tests.

### [5] Precautions

(1) Temperature for soldering the lead wire shall not exceed 300°C and the soldering time shall be within 5 seconds.

(2) Position to be soldered: Solder only the position where the lead wire is

1.0mm away from the glass seal.

Do not solder the case.

(3) Cutting, bending and

correction of lead wire: The glass seal shall be free of any crack or other

damage which may deteriorate the characteristics

of RESONATORS.

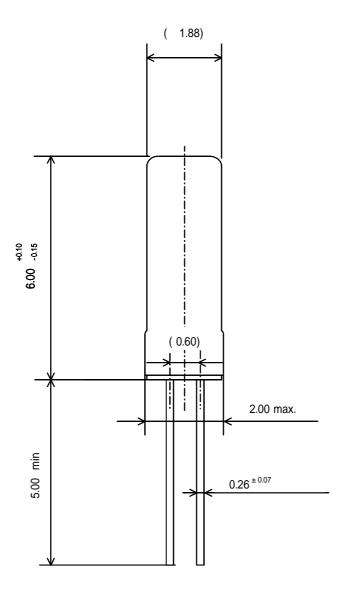
## [6] Outgoing inspection standard

•The outgoing inspection shall be conducted as per the following standard .

•The sampling shall be performed according to the ANSI/ASQCZ1.4-1996 .

No	Item	Sampling level	AQL(%)	
1	Frequency tolerance	I	1.0	
2	Equivalent series resistance	I	1.0	
3	Outer appearance	I	1.5	
4	Others characteristics	Periodical quality inspection		

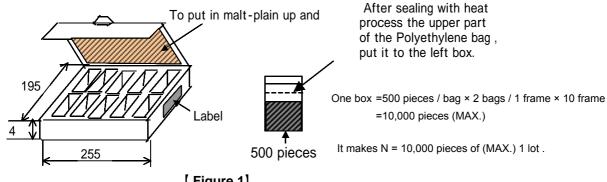
# [7] Out Line Drawing



		IB	
DESCRIPTION	Materials	Remarks	REMARKS
VT-200-F	Ni SnCu(2 ~ 5%Cu)		UNIT: 1=1 mm

# Article method and packing structure

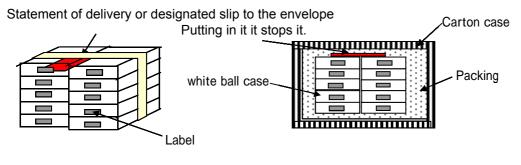
- Bag checkmate packing specification
- 1) White ball case (the inner compartment) the packing structure



[ Figure 1]

- 2. Outer case packing specification (the sectional plan) [Figure 3]
- 1) The number of Carton case (the outer case) size and white ball case (the inner compartment) [ Table 1 ] [Figure 2]

<u> </u>	able 1			
The outer case	S	B - 4	G - 2 M A (W carton case	D (W carton case)
Number of white ball				
case	1 box	3 boxes	10 boxes	20 boxes



[ Figure 3] [ Figure 2]

3. Sample of the label display (display department, please refer to [Figure 1] [ Figure 2] )

	PART	VT-200-F
Product bar code	LOTNo.	
	Quantity	10,000 pcs
Item bar code *	Calibre	32.768kHz
		32.768kHz 12.5pF /±20 × 10 <sup>-6</sup>
Quantity Lot. No. bar code	Remark	3

PART : Our company product name

LOT No. : Lot No. display

Quantity: Quantity

Calibre : Frequency, CL value, F0 deviatior

Remarks: Marking etc. : Item code

#### 4 . Storage environment

A product avoids the direct ray and please store with the normal temperature and humidity . Conformance in (the standard condition of the JIS Z8703 test place)